
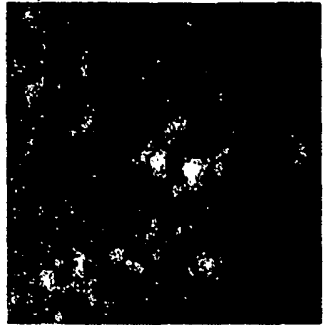
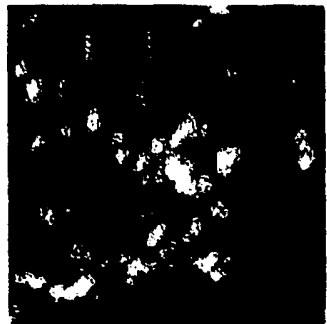

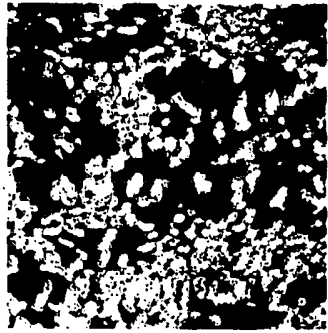
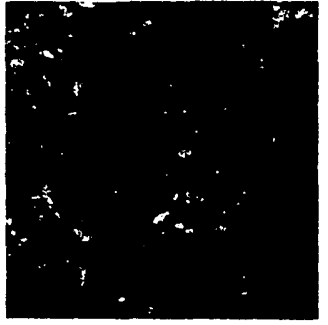
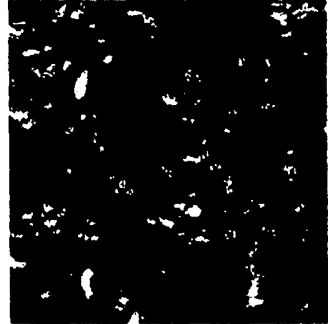



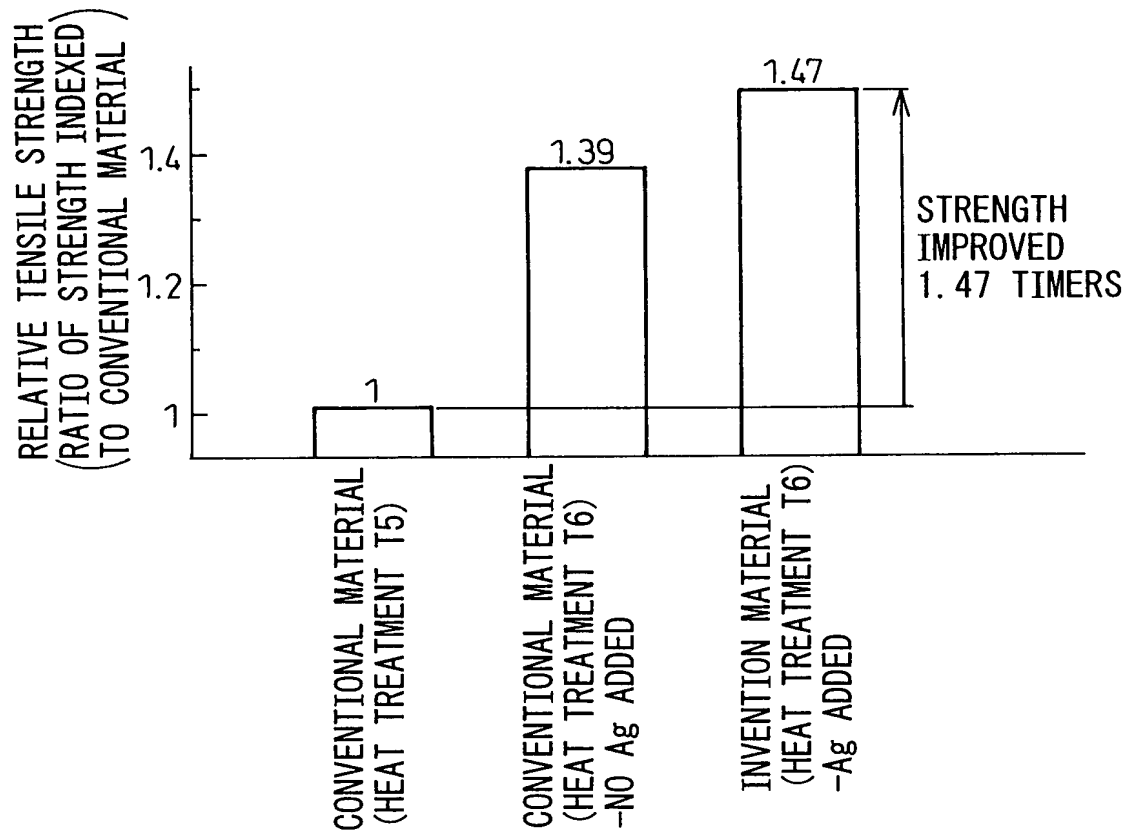
Fig.1 (a) (b) (c) (d)

	EUTECTIC Si DISTRIBUTION	Cu DISTRIBUTION	Mg DISTRIBUTION	Fe DISTRIBUTION
COMPARATIVE EXAMPLE (NO Ag ADDED)				
AVERAGE PARTICLE SIZE	13μm	9μm	15μm	10μm
INVENTION EXAMPLE (Ag ADDED)				
AVERAGE PARTICLE SIZE	10μm	6μm	10μm	5μm

(e) (f) (g) (h)

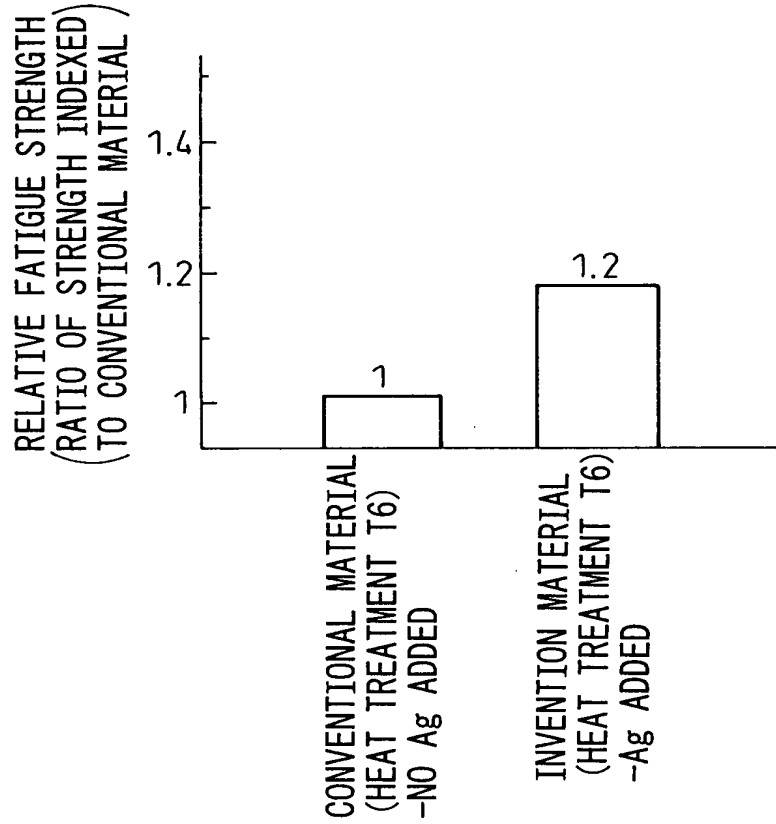
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Fig.2A

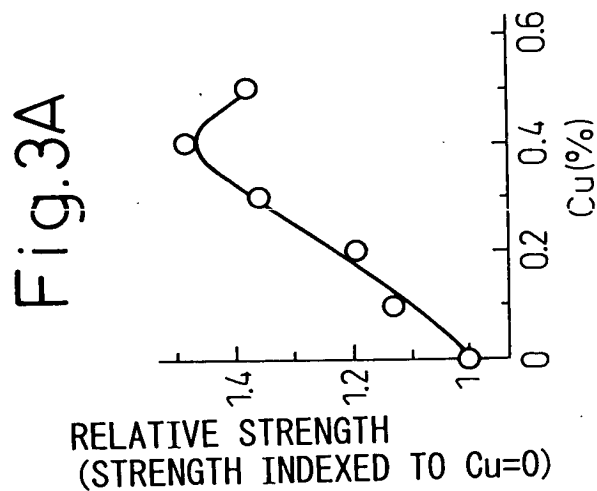
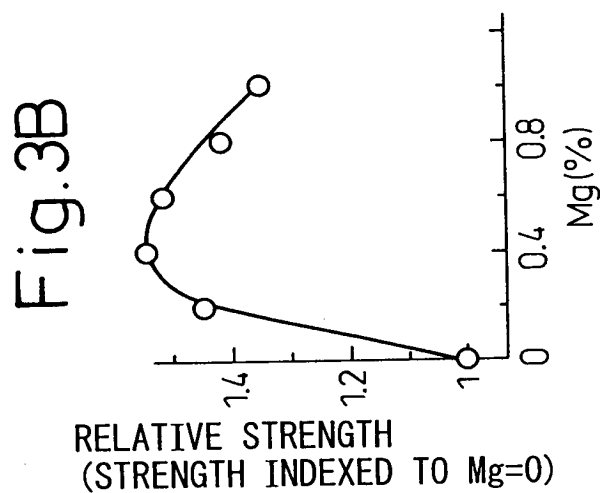
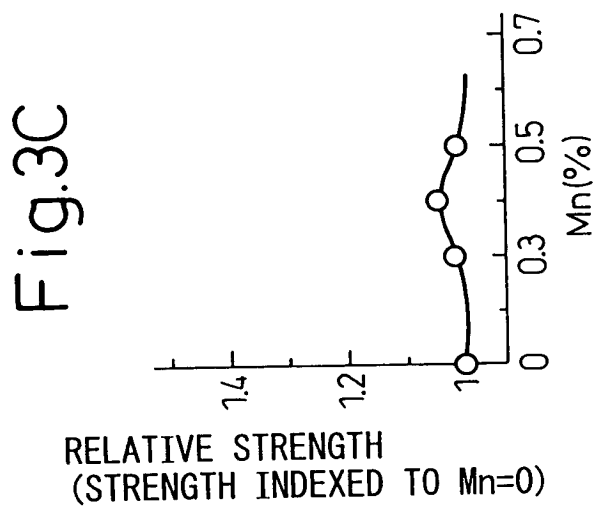


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Fig.2B



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Fig.4B

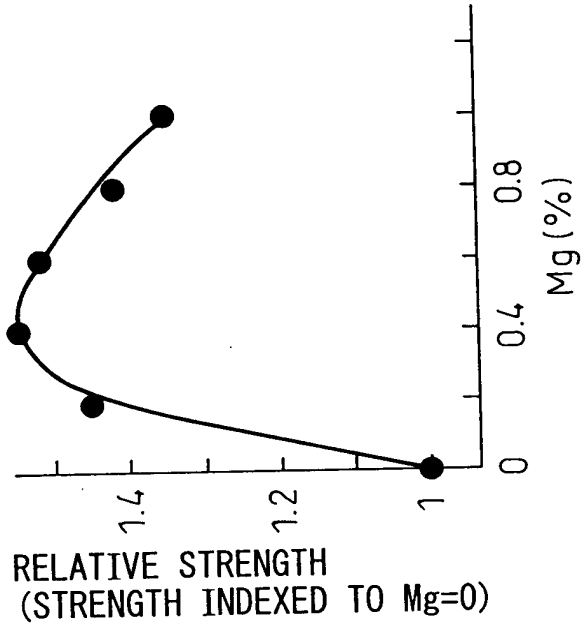
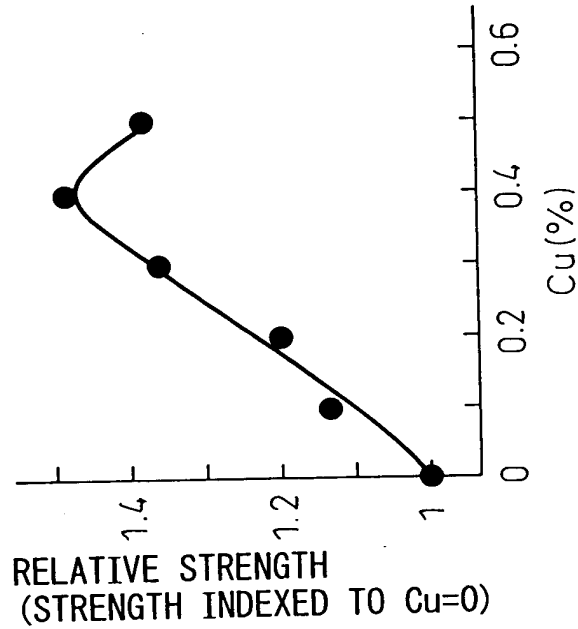


Fig.4A



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Fig.5

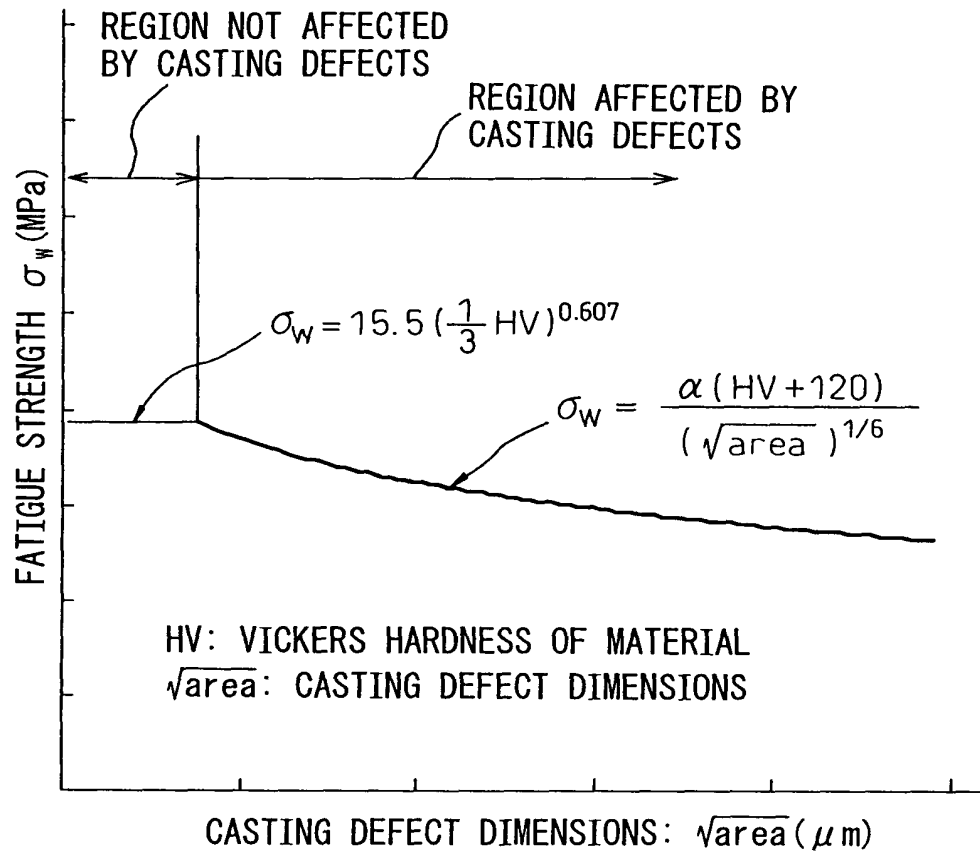


Fig.6A

EUTECTIC Si INGREDIENT



T6 TREATMENT
COMPARATIVE EXAMPLE

Fig.6B

EUTECTIC Si INGREDIENT



T6 (NCDE ADDED)
INVENTION EXAMPLE
(LARGE EFFECT OF INCREASED)
(FINENESS OF DISPERSION)

Fig. 7A

INVENTION
EXAMPLE (T6)
(NCDE ADDED)

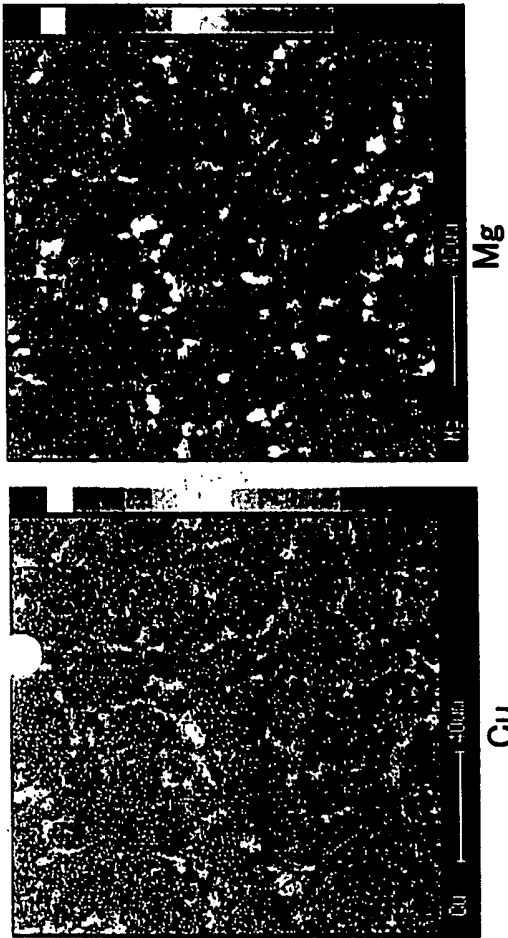
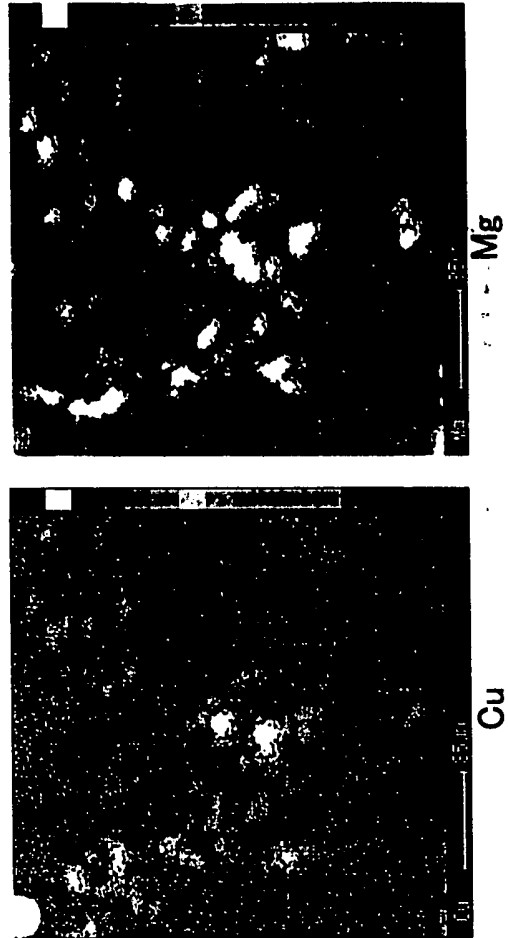


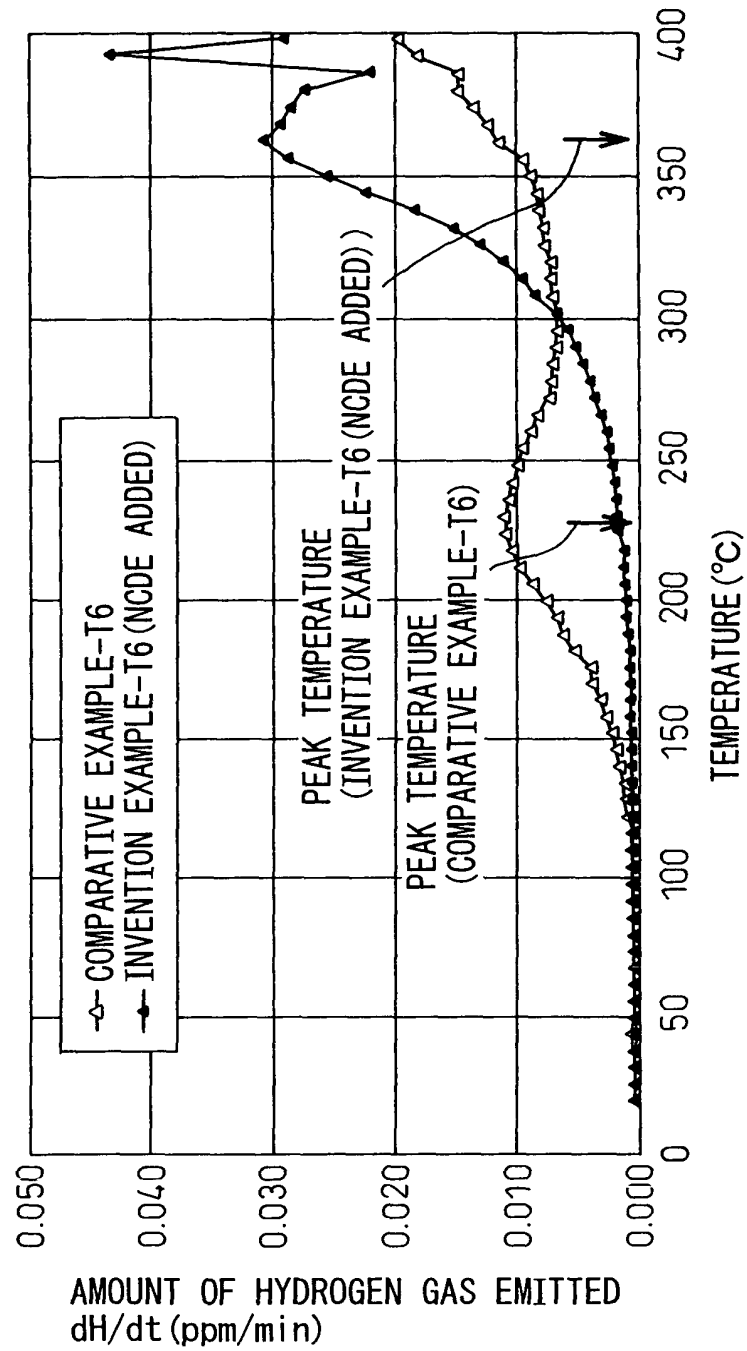
Fig. 7B

COMPARATIVE
EXAMPLE (T6)
(NCDE NOT ADDED)



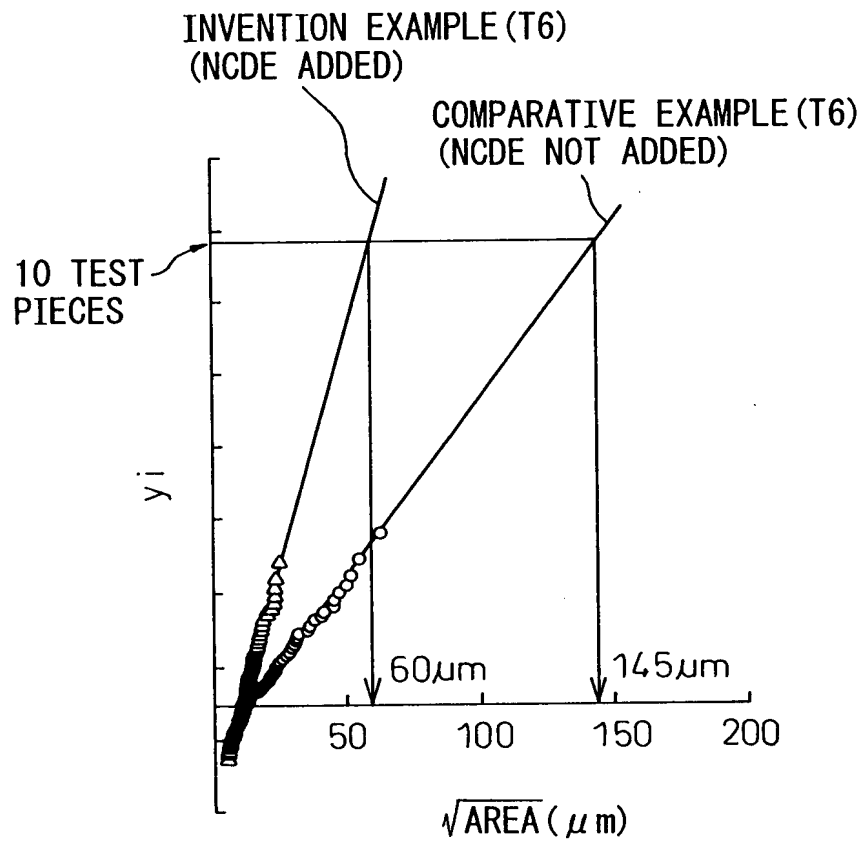
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Fig.8



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Fig.9



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Fig.10

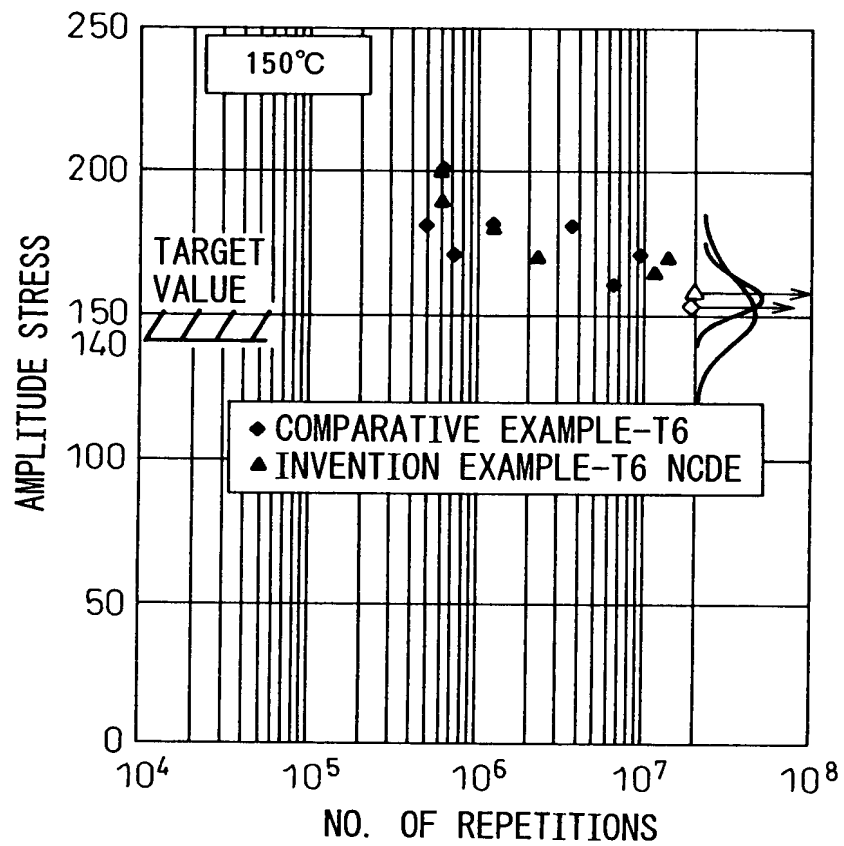
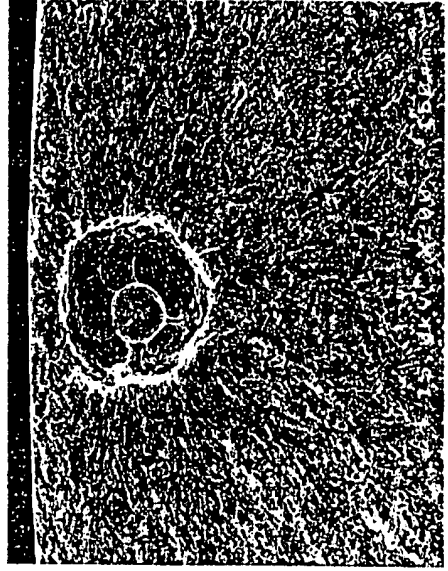
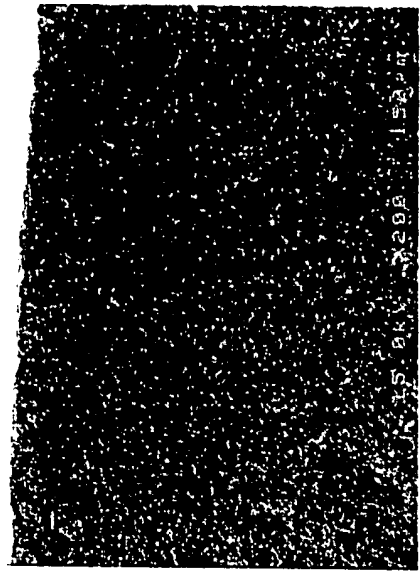


Fig.11A



COMPARATIVE
EXAMPLE (T6)

Fig.11B



INVENTION
EXAMPLE (T6)
-NCDE ADDED

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Fig.12B

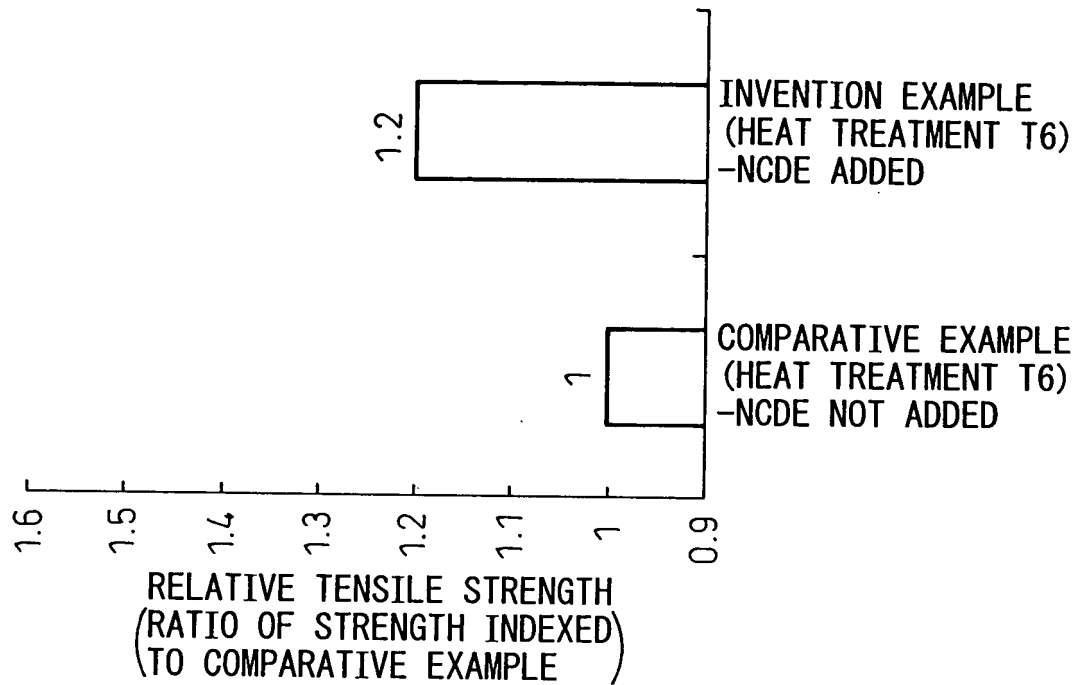


Fig.12A

